

# MEM6810 Engineering Systems Modeling and Simulation



## 工程系统建模与仿真

Theory Analysis

### Lecture 5: Input Modeling

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(Sino-US Global Logistics Institute)



- 1 Introduction
- 2 Data Collection
- 3 Identifying Distribution
  - ▶ Physical Basis of Distributions
  - ▶ Histogram and Bar Chart
- 4 Distribution Fitting
  - ▶ Method of Moments
  - ▶ A Simple Variation of MoM
  - ▶ Maximum Likelihood Estimation
- 5 Goodness of Fit
  - ▶ Graphical Methods
  - ▶ Statistical Tests
  - ▶ Remarks
- 6 An Illustrative Example



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- The quality of outputs is no better than the quality of inputs.
  - *“Garbage in, garbage out.”*
- *“All models are wrong, but some are useful.”* – George Box.
  - There is no “true” model for any stochastic input.
  - The best we can do is to obtain an approximation that yields reasonable and useful results.

- Fundamental requirements for an input model:
  - can capture the physical properties of the system;
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- Input modeling is sometimes more of an art than an engineering.
  - It nearly always requires the analysts to use their judgment as well as to apply appropriate statistical tools.
  - Since there is no “true” model, it is sensible to run the simulation with several plausible input models to see if the conclusions are robust or highly sensitive to the choices.

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  - ⑤ If the fit is not good, select another candidate and go to Step 3, or use an empirical distribution.



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- **Never** trust data blindly!
  - A common mistake is to simply throw data into a software and ask for a “best” fit model.
  - Always take into account under what context (e.g., time, potential influence of other factors) the data was collected.

- The collected data can be
  - stale (out of date);
  - “dirty” (containing errors);
  - unexpected;
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- Sometimes the effort or cost to transform data into a usable form, or “clean” data, can be as significant as that required to obtain them.

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  - Collect input data, not output data.
    - Example: customer arrival times and service times are input, whereas waiting times are output.

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- Do not ignore the physical characteristics of the process when selecting distributions.
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  - Is it bounded or is there no natural bound?
- There are literally hundreds of probability distributions that have been created; many were created with some specific physical process in mind.

- Discrete Distributions:
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  - **Poisson**: Models the number of independent events that occur in a fixed amount of time or space.
    - *Example 1*: the number of customers that arrive to a store during 1 hour.
    - *Example 2*: the number of defects found in 30 square meters of sheet metal.

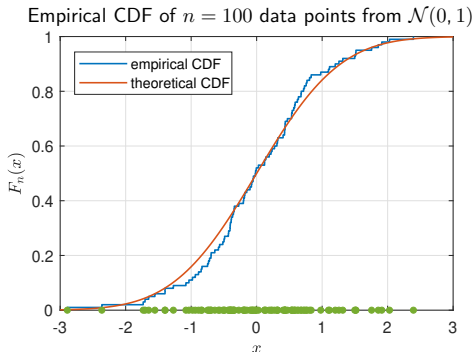
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  - **empirical distribution**: Often used when no theoretical distribution seems appropriate.

- The CDF of the **empirical distribution** (empirical CDF) is defined as

$$F_n(x) = \frac{\text{number of points } \leq x}{n} = \frac{1}{n} \sum_{i=1}^n \mathbb{1}_{\{x_i \leq x\}}.$$

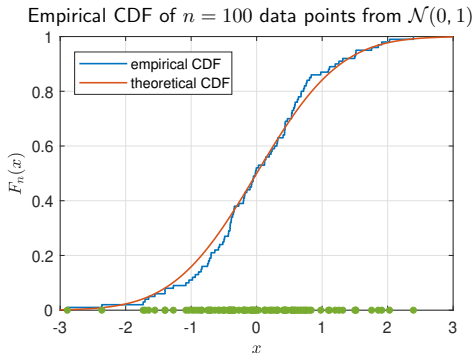
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- The empirical CDF is a right-continuous step function.

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  - **exponential**: Models the time between independent events, or a process time that is memoryless.
    - *Example 1*: the times between the arrivals from a large population of potential customers who act independently.
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  - **Weibull**: Models the time to failure for components.
    - *Note*: the failure rate can be increasing, decreasing, or constant (reduce to exponential distribution).

- Continuous Distributions:
  - **Erlang**: Models the time that can be viewed as the sum of several exponentially distributed times.
    - *Example*: a computer network fails when a computer and two backup computers fail, and each has exponentially distributed time to failure.
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  - **triangular**: Models a process for which only the minimum, most likely, and maximum values of the distribution are known.
    - *Example*: only the minimum, most likely, and maximum time required to test a product are known.

- Useful in determining the shape of the distribution from which the data have been sampled:
  - **Histogram** describes frequency or relative frequency (i.e., ratio) of (usually continuous) data in different ranges.
  - **Bar chart** (or bar graph) describes frequency or relative frequency of data among discrete categories.



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- For continuous data:
  - Histogram corresponds to the pdf of a theoretical distribution.
  - In terms of the *shape*, not the exact *value*!<sup>†</sup>
- For discrete data:
  - Usually use bar chart instead of histogram.
  - Bar chart corresponds to the pmf of a theoretical distribution.
  - In terms of both the *shape* and *value* (if the bar chart uses relative frequency).

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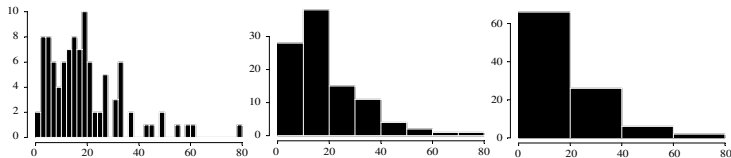


Figure: Ragged, Appropriate and Coarse Histograms (from [Banks et al. \(2010\)](#))

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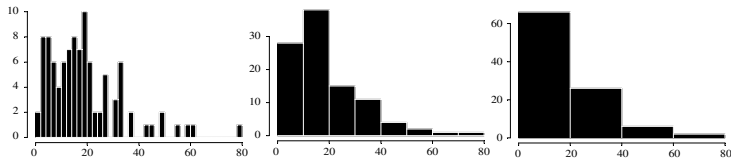


Figure: Ragged, Appropriate and Coarse Histograms (from [Banks et al. \(2010\)](#))

- Choosing the number of intervals approximately equal to the square root of the sample size often works well in practice ([Hines et al. 2002](#)).

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- After a family of distributions has been selected, the next step is to determine the parameters of the distribution that can “best” fit the data.
  - Called distribution fitting, or parameter estimation.
- There are many different approaches and we discuss two simple ones:
  - method of moments (MoM)
  - maximum likelihood estimation (MLE)

- For a random variable  $X$ , its  $k$ th moment is defined as  $\mathbb{E}[X^k]$ .

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- Let  $X_1, \dots, X_n$  be a random sample of  $X$ . The  $k$ th sample moment is defined as

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- Suppose the considered distribution family has  $s$  unknown parameters.
  - ① Analytically compute  $\mathbb{E}[X^1], \dots, \mathbb{E}[X^s]$ , as functions of those parameters.
    - *Note:* the moments of common distributions are well-known.
  - ② Compute  $m_1, \dots, m_s$  from the data.
  - ③ Solve  $\mathbb{E}[X^k] = m_k$ ,  $k = 1, \dots, s$ , for  $s$  unknown parameters.

- Example 1: Suppose  $X_1, \dots, X_n$  are iid from  $\text{Gamma}(\alpha, \lambda)$  (in shape & rate parametrization).
  - Recall:  $f(x) = \frac{\lambda^\alpha}{\Gamma(\alpha)} x^{\alpha-1} e^{-\lambda x}$ ,  $\mathbb{E}[X] = \alpha/\lambda$ ,  $\text{Var}(X) = \alpha/\lambda^2$ .  
Estimate  $\alpha$  and  $\lambda$  using MoM.

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Estimate  $\alpha$  and  $\lambda$  using MoM.

Solution. The first two moments are

$$\mathbb{E}[X] = \alpha/\lambda = m_1,$$

$$\mathbb{E}[X^2] = \text{Var}(X) + (\mathbb{E}[X])^2 = (\alpha + \alpha^2)/\lambda^2 = m_2.$$

Solving two equations yields MoM estimators

$$\hat{\alpha} = \frac{m_1^2}{m_2 - m_1^2}, \quad \hat{\lambda} = \frac{m_1}{m_2 - m_1^2}. \quad \blacksquare$$

- Example 2: Suppose  $X_1, \dots, X_n$  are iid from  $\text{Exp}(\lambda)$ . Estimate  $\lambda$  using MoM.

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Solution. The first moment is

$$\mathbb{E}[X] = 1/\lambda = m_1.$$

So the MoM estimator of  $\lambda$  is  $\hat{\lambda} = \frac{1}{m_1} = \frac{n}{X_1 + \dots + X_n}$ . ■



- Example 3: Suppose  $X_1, \dots, X_n$  are iid from  $\mathcal{N}(\mu, \sigma^2)$ . Estimate  $\mu$  and  $\sigma^2$  using MoM.

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$$\begin{aligned}\mathbb{E}[X] &= \mu = m_1, \\ \mathbb{E}[X^2] &= \text{Var}(X) + (\mathbb{E}[X])^2 = \sigma^2 + \mu^2 = m_2.\end{aligned}$$

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$$\hat{\mu} = m_1, \quad \hat{\sigma}^2 = m_2 - m_1^2. \quad \blacksquare$$

- Example 3: Suppose  $X_1, \dots, X_n$  are iid from  $\mathcal{N}(\mu, \sigma^2)$ . Estimate  $\mu$  and  $\sigma^2$  using MoM.

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$$\hat{\mu} = m_1, \quad \hat{\sigma}^2 = m_2 - m_1^2. \quad \blacksquare$$

- Remark:  $\hat{\mu} = \frac{\sum_{i=1}^n X_i}{n}$ , and

$$\begin{aligned}\hat{\sigma}^2 &= \frac{X_1^2 + \dots + X_n^2}{n} - \bar{X}^2 = \frac{\sum_{i=1}^n X_i^2 - n\bar{X}^2}{n} \\ &= \frac{\sum_{i=1}^n (X_i - \bar{X})^2}{n}.\end{aligned}$$

(why?)



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- Many common distributions have no more than 2 parameters:  
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Erl( $k, \lambda$ ), Gamma( $\alpha, \lambda$ ), Beta( $\alpha, \beta$ ), Weibull( $\alpha, \beta$ ),  $\mathcal{N}(\mu, \sigma^2)$ ,  $t_p$ ,  
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- Revisit Example 1:  $\text{Gamma}(\alpha, \lambda)$ .

Recall: using MoM,  $\hat{\alpha} = \frac{m_1^2}{m_2 - m_1^2}$ ,  $\hat{\lambda} = \frac{m_1}{m_2 - m_1^2}$ .



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- Remarks:
  - If  $X_1, \dots, X_n$  haven't been observed,  $\lambda^* = n/(X_1 + \dots + X_n)$ .
  - The estimator is the same as in MoM.



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- For discrete distributions, replace the pdf with pmf.



- 1 Introduction
- 2 Data Collection
- 3 Identifying Distribution
  - ▶ Physical Basis of Distributions
  - ▶ Histogram and Bar Chart
- 4 Distribution Fitting
  - ▶ Method of Moments
  - ▶ A Simple Variation of MoM
  - ▶ Maximum Likelihood Estimation
- 5 Goodness of Fit**
  - ▶ Graphical Methods
  - ▶ Statistical Tests
  - ▶ Remarks
- 6 An Illustrative Example



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- Try more than one plot/test before making conclusion.



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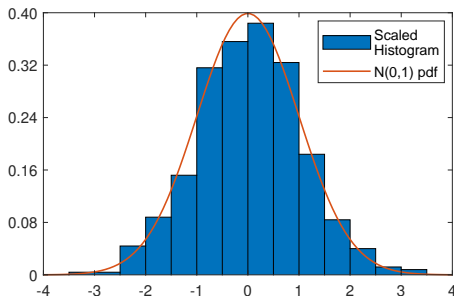


Figure: Example of Scaled Histogram vs. Fitted pdf

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- The  $q$ -quantile of  $X$  is that value  $\gamma$  such that  $\mathbb{P}(X \leq \gamma) = F(\gamma) = q$ , for  $0 < q < 1$ . When  $F(x)$  has an inverse, we can write  $\gamma = F^{-1}(q)$ .
  - Median: 50% quantile.
  - In financial risk management, quantile of the profit-and-loss of a portfolio is also called Value-at-Risk (VaR).

- To make Q-Q plots, given the data  $\{x_1, \dots, x_n\}$  and the fitted distribution with CDF  $F(x)$ :
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  - If the data is indeed generated from distribution  $F(x)$ , then

$$y_j \approx F^{-1}\left(\frac{j - 0.5}{n}\right),$$

so the plot will be approximately a straight line with slope 1.

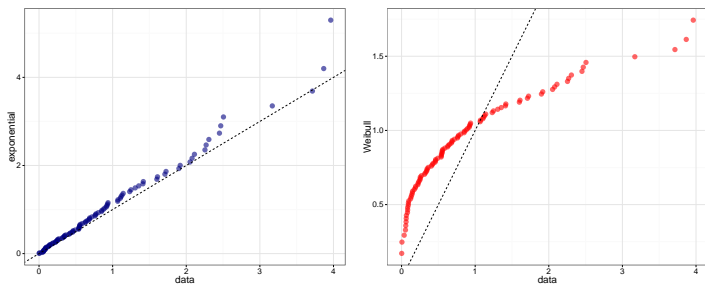


Figure: Examples of Q-Q Plot (from [ZHANG Xiaowei](#))

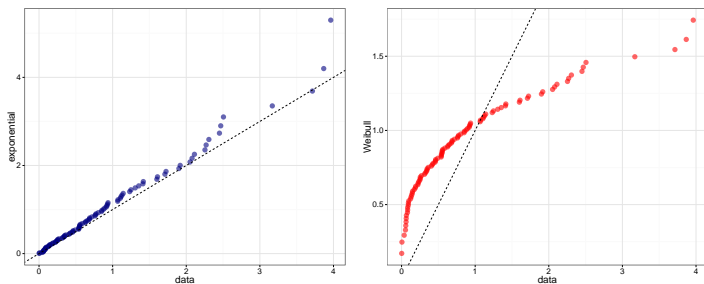


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- The observed values will never fall exactly on a straight line
- The ordered values are not independent because they are ranked. Hence, if one point lies above the line, it is likely that the next one will too.
- The values at the extremes have a much higher variance than those in the middle. So greater discrepancies can be acceptable at the extremes; linearity in the middle is much more important.

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Decision \ Truth	reject $H_0$	fail to reject $H_0$
$H_0$ is true	type I error	correct
$H_1$ is true	correct	type II error



- A hypothesis test only directly controls the type I error.
  - A test with the same type I error probability but smaller type II error probability is better (*more powerful*).
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  - the computed test statistic falls in certain range (called *rejection region*), which is determined by  $\alpha$ .

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  - ④ Reject  $H_0$  if  $R$  is too large.
    - Reason: A large value of  $R$  indicates a poor fit, whereas a small value indicates a good fit.
    - Question: How large is too large? (i.e., what is the rejection region?)



- View the test statistic  $R$  as a random variable.
  - Since we assume the collected data is one observed random sample from some unknown distribution, if we conduct the study multiple times, the values of the statistics will be different because the collected data will be different.
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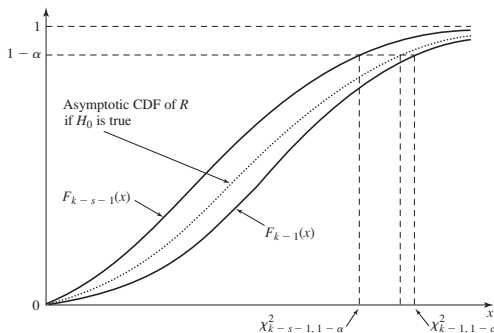


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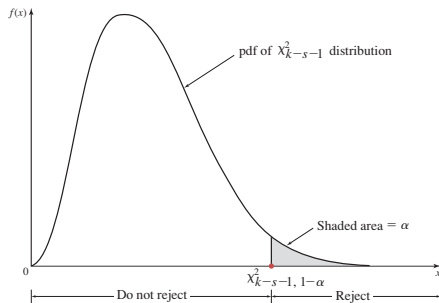
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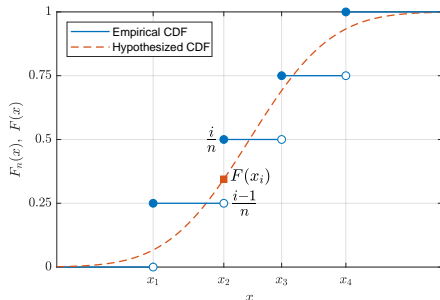
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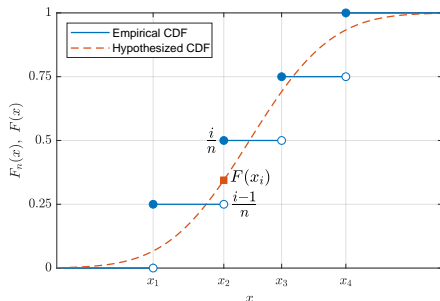
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- In the absence of a definitive guideline for choosing the intervals, it's usually recommended to make  $E_i$  equal (or approximately equal) and no less than 5, for all intervals.

- The **Kolmogorov-Smirnov test** (K-S test, 柯尔莫哥洛夫-斯米尔诺夫检验) formally compares the empirical CDF  $F_n(x)$  with the CDF of the hypothesized distribution,  $F(x)$ .

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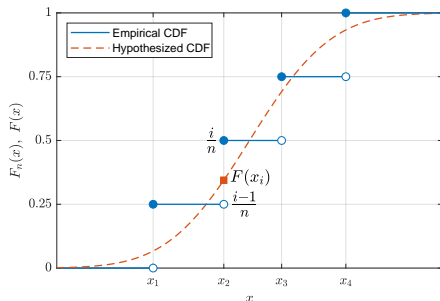


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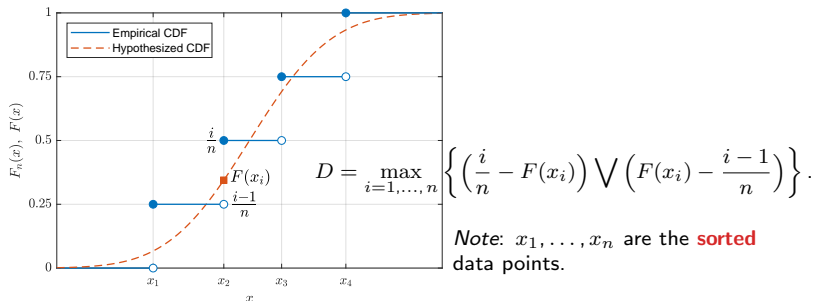
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  - Given  $H_0$  is true, the distribution of  $D$  depends on  $F(x)$ , and it is complicated.
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- Advantage of K-S test:
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- K-S test is relatively more convenient to be used in a case where the hypothesized distribution is continuous and no parameter is estimated. For example:
  - Test random number generators.
  - Test a Poisson process (more details later).

- Comments on  $p$ -value:
  - $p$ -value can be viewed as a measure of fit: a large  $p$ -value tends to indicate a good fit, while a small  $p$ -value suggests a poor fit.
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  - Different statistical tests may give different  $p$ -values.
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- Comments on general goodness-of-fit tests:
  - If very little data are available, then a goodness-of-fit test is unlikely to reject any candidate distribution.
    - No enough evidence to reject  $H_0$ .
  - If a lot of data are available, then a goodness-of-fit test is likely to reject all candidate distributions.
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    - $H_0$  is virtually never exactly true, and even a tiny departure from the hypothesized distribution will be detected for large  $n$ .
  - Do not have blind faith in goodness-of-fit tests!
    - Failing to reject a candidate distribution should be taken as only **one piece of evidence** in favor of that choice.
    - Rejecting a candidate distribution should be taken as only **one piece of evidence** against the choice.

- Graphical Methods vs. Statistical Tests
  - Graphical methods *qualitatively* measure the fitting goodness, while statistical tests *quantitatively* measure the fitting goodness.
  - Statistical tests measure the lack of fit by summary statistics, while graphical methods show where the lack of fit occurs (body, left tail, right tail) and allow users to decide whether it is important.
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- Always combine statistical test results with graphical analysis.
- When no model fits the data satisfactorily, we may end up with the empirical distribution.

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  - It recommends the “best” distribution in its library based on summary measure like the  $p$ -value (and perhaps other factors such as discrete or continuous, bounded or unbounded).
- Always keep the following in mind when using such an option:
  - The software might know nothing about the physical basis of the data.
  - Automated best-fit procedures tend to choose the more flexible distributions (gamma over Erlang, Weibull over exponential).
  - But, close conformance to the data does not always lead to the most appropriate input model (overfitting).
  - The limitation of summary measure like  $p$ -value.
  - View the automated distribution selection as one suggestion, inspect it using graphical methods, and remember that *the final choice is yours*.

- All the graphical methods and statistical tests can be used to check the uniformity of a random number generator (RNG).
  - ① Generate a sequences of numbers (as many as you want) using the RNG.
  - ② Check if  $\text{Unif}(0, 1)$  fits the data well enough.



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    - Given  $N(T) = n$ , the  $n$  arrival times  $S_1, \dots, S_n$  have the same distribution as  $n$  independent RVs from  $\text{Unif}(0, T)$  that are **sorted**.

- 1 Introduction
- 2 Data Collection
- 3 Identifying Distribution
  - ▶ Physical Basis of Distributions
  - ▶ Histogram and Bar Chart
- 4 Distribution Fitting
  - ▶ Method of Moments
  - ▶ A Simple Variation of MoM
  - ▶ Maximum Likelihood Estimation
- 5 Goodness of Fit
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- 6 An Illustrative Example



# An Illustrative Example

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## ① Data Collection.

- Perform life tests on a random sample ( $n = 50$ ) of electronic components and record their lifetime, in days:

79.919	3.081	0.062	1.961	5.845
3.027	6.505	0.021	0.013	0.123
6.769	59.899	1.192	34.760	5.009
18.387	0.141	43.565	24.420	0.433
144.695	2.663	17.967	0.091	9.003
0.941	0.878	3.371	2.157	7.579
0.624	5.380	3.148	7.078	23.960
0.590	1.928	0.300	0.002	0.543
7.004	31.764	1.005	1.147	0.219
3.217	14.382	1.008	2.336	4.562

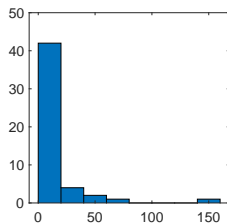
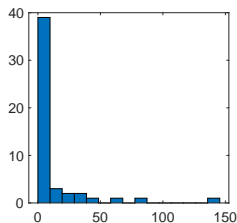
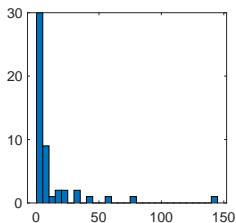
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- Lifetime, although recorded to three-decimal-place accuracy, is a positive continuous variable.
- For this life time, naturally, exponential and Weibull are considered.



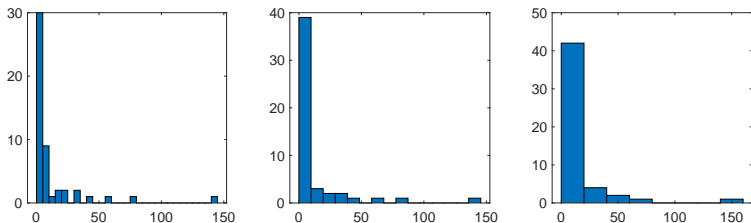
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- We decide to first try exponential distribution family  $\text{Exp}(\lambda)$ .

## ③ Distribution Fitting.

- Recall Example 2, MoM (or its variation) and MLE yield the same estimator for  $\lambda$ , which is  $\hat{\lambda} = \frac{n}{X_1 + \dots + X_n}$ .
- Plug the data in, and the estimate of  $\lambda$  is 0.084.

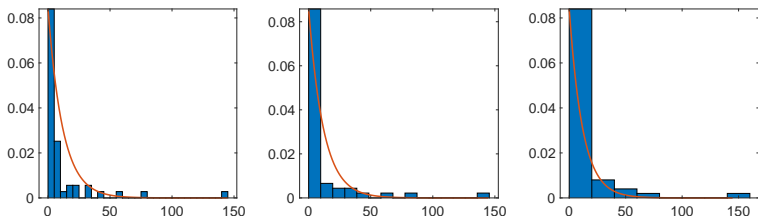
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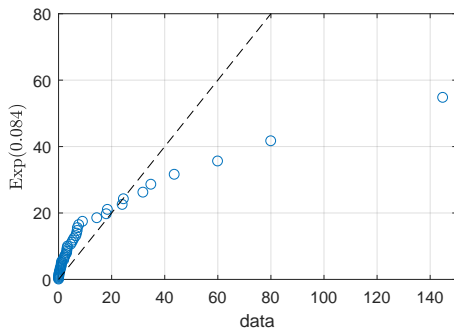
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- Scaled histogram vs. pdf of  $\text{Exp}(0.084)$ .



## ④ Goodness of Fit.

- Q-Q plot.



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<i>Class Interval</i>	<i>Observed Frequency</i> $O_i$	<i>Expected Frequency</i> $E_i$	$\frac{(O_i - E_i)^2}{E_i}$
[0, 1.590)	19	6.25	26.01
[1.590, 3.425)	10	6.25	2.25
[3.425, 5.595)	3	6.25	0.81
[5.595, 8.252)	6	6.25	0.01
[8.252, 11.677)	1	6.25	4.41
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So,  $p$ -value =  $\mathbb{P}(R \geq r) = \mathbb{P}(R \geq 39.6) = 5 \times 10^{-7}$ .

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Hence, at almost any practical level of significance, e.g.,  
 $\alpha = 0.05$ ,  $\alpha = 0.01$ , we will reject  $H_0$ .